

### US00D500695S

# (12) United States Design Patent (10) Patent No.:

Wrisley et al.

US D500,695 S

### (45) Date of Patent:

Jan. 11, 2005

#### HOUSING FOR TEST AND MEASUREMENT (54)**INSTRUMENTS**

| (75) | Inventors: | Jerry L. Wrisley, Beaverton, OR (US); |
|------|------------|---------------------------------------|
|      |            | Takashi Sugiura, Kanagawa (JP)        |

### Assignee: Tektronix, Inc., Beaverton, OR (US)

14 Years Term:

Appl. No.: 29/204,635

Apr. 30, 2004 Filed: (22)

| (51) | LOC (7) Cl | 10-04 |
|------|------------|-------|
| (52) | U.S. Cl D  | 10/76 |

(58)324/102, 112, 121 R; 340/734, 747, 798;

354/487

#### **References Cited** (56)

### U.S. PATENT DOCUMENTS

| D413,823  | $\mathbf{S}$ | * | 9/1999 | Dobyns et al.  | D10/76 |
|-----------|--------------|---|--------|----------------|--------|
| D420,607  | $\mathbf{S}$ |   | 2/2000 | Wrisley et al. |        |
| D460,371  | $\mathbf{S}$ | * | 7/2002 | Wrisley et al. | D10/78 |
| D460,703  | S            | * | 7/2002 | Wrisley et al. | D10/78 |
| 6,437,552 | <b>B</b> 1   | * | 8/2002 | Sekel et al    |        |
| D472,171  | S            | * | 3/2003 | Wrisley et al. | D10/76 |

<sup>\*</sup> cited by examiner

Primary Examiner—Antoine D. Davis (74) Attorney, Agent, or Firm—William K. Bucher

#### (57)CLAIM

The ornamental design of a housing for test and measurement instruments, as shown and described.

#### DESCRIPTION

The ornamental design disclosed in this application is for a housing for test and measurement instruments, such as oscilloscopes, logic analyzers, waveform generators, and the like. The housing has a substantially rectangular front face with a substantially rectangular opening disposed in a portion thereof, side surfaces having a curved top edges, and a top surface having curved surfaces adjacent to the curved top edges of the side surfaces that transition to a substantially flat surface extending from the front face to the rear surface having a recess formed therein for receiving a recessed handle.

- FIG. 1 is a perspective view of a housing for test and measurement instruments;
- FIG. 2 is a front elevation view of the housing for test and measurement instruments;
- FIG. 3 is a left side elevation view of the housing for test and measurement instruments;
- FIG. 4 is a right side elevation view of the housing for test and measurement instruments;
- FIG. 5 is a top plan view of the housing for test and measurement instruments;
- FIG. 6 is a bottom plan view of the housing for test and measurement instruments; and,
- FIG. 7 is a rear elevation view of the housing for test and measurement instruments.

## 1 Claim, 6 Drawing Sheets















